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NOTES/COMMENTS:

Per our conversation of even date, enclosed is copy of the patent application 98 7501 US 01 filed September 16, 2002

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
ATTY.'S DOCKET: 98 P 7501 US 01

Control 2011.7

In re the application of:

Ramachandran et al.

Serial No.: 09/204,706

Examiner: A. Olsen

Filing Date: December 3, 1998)

Title: REMOVAL OF POST-RIE POLYMER)
ON AL/CU METAL LINE)

#230-NE 3/25/03 mw

AMENDMENT UNDER 37 C.F.R. §1,116

Honorable Commissioner of Patents and Trademarks Washington, D.C. 20231

Sir:

In reply to the Office Action mailed September 10, 2002, which rejected the claims in the above-identified patent application, applicants respectfully request reconsideration, based upon the amendments hereinafter set forth.

IN THE CLAIMS:

(5th Amendment) In a metal etch tool for removing post-RIE polymer rails formed on a Al/Cu metal line of a semiconductor structure, the improvement comprising:

- [1] an integrated metal etch tool interfaceable with:
- a) strip chamber means [for water only plasma] to strip photo-resist of a semiconductor composite structure subsequent to a RIE to limit thickness of sidewall polymer rails;
- b) vacuum chamber means to chemically modify sidewall polymer rails [by supplying a mixture of an etching gas/acid neutralizing gas of] with HF/NH3 to form a water soluble

